Thanking the TOS Associated Editors and Reviewers

To many of us, 2020 may be a year that we would like to forget. Our lives have been immensely altered by the COVID-19 pandemic, with some of us having to suffer losses of our close ones. But life moves on, and as we publish our first issue of ACM Transactions on Storage for 2021, we look for hope and encouragement. In this light, I take this opportunity to express my appreciation to all those who have worked to make ACM TOS, the premier journal it is today. In particular, I thank the Associate Editors and the reviewers who have voluntarily devoted their time and effort to serve the community. Our entire community is indebted to these volunteers, who have generously shared their expertise to handle and thoroughly review the articles that were submitted. In the past two years, ACM TOS received the help of over 31 Editorial Board members along with 178 invited reviewers to curate nearly 117 submissions and publish more than 48 articles with meaningful and impactful results.

While the Associate Editors and all the reviewers over the past two years have been listed in our website, <https://tos.acm.org/>, I take this opportunity to list our distinguished reviewers, who went out of their way to provide careful, thorough, and timely reviews. These names are based on the recommendations of the Associate Editors, through whom the reviews were solicited. Again, we thank all the reviewers for their dedication and support to ACM TOS and the computer system storage community as a whole. Thank you all.

Distinguished Reviewers

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Sang-Hoon Kim, Ajou University, Korea

Sudarsun Kannan, Rutgers University, USA

Wen Xia, Harbin Institute of Technology, China

Youngjin Kwon, Korea Advanced Institute of Science and Technology, Korea

Sam H. Noh

Editor-in-Chief